



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L CEP 25.0002

CB Certificate No.: IECQ-L 2025.008

Schedule Number: IECQ-L CEP 25.0002-S

Rev No.: 1

Revision Date: 2025/05/21

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№	Products, Materials	Items,Parameter		Title, Code of specification, standard or method used
		NO.	Name	
1	Electronic Components	1	High Temperature Storage Life	High Temperature Storage Life JESD22-A103E.01-2021
		2	Low Temperature Storage Life	Low Temperature Storage Life JESD22-A119A-2015
		3	Steady State Temperature Humidity Test	Steady State Temperature Humidity Bias Life Test JESD22-A101D.01-2021
		4	Temperature Cycling	Temperature Cycling JESD22-A104F.01-2023
				Power and Temperature Cycling JESD22-A105D-2020
		5	Highly Accelerated Temperature and Humidity Test	Accelerated Moisture Resistance -Unbiased HAST JESD22-A118B.01-2021
				Highly Accelerated Temperature and Humidity Stress Test JESD22-A110E.01-2021
		6	Accelerated Moisture Test	Accelerated Moisture Resistance - Unbiased Autoclave JESD22-A102E-2015
		7	Temperature, Bias, and Operating Life	Temperature, Bias, and Operating Life JESD22-A108G-2022
		8	Acoustic Microscopy	Acoustic Microscopy for Nonhermetic Encapsulated Electronic Components J-STD-035A-2022
		9	precondition	Moisture/Reflow Sensitivity Classification for Nonhermetic Surface Mount Devices J-STD-020F-2022
				Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing JESD22-A113I-2020
		10	Early Life Failure Rate	Early Life Failure Rate AEC - Q100-008 - REV-A-2003
		11	HBM	For Electrostatic Discharge Sensitivity Testing Human Body Model (HBM)-Component Level ANSI/ESDA/JEDEC JS-001: 2023

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China Electronic Product Reliability and Environmental Testing Research Institute (CEPREI)

No. 76 West of Zhucun Avenue, Zhucun, Zengcheng District, Guangzhou 511370 China



IECQ-L Schedule of Scope Rev. 01



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				Human Body Model Electrostatic Discharge Test AEC-Q100-002 REV-E:2013
				Human Body Model (HBM) Electrostatic Discharge (ESD) Test AEC-Q101-001 REV-A:2005
				Electrostatic discharge sensitivity classification MIL- STD-883-3:2019
		12	CDM	For Electrostatic Discharge Sensitivity Testing Charged Device Model (CDM) - Device Level ANSI/ESDA/JEDEC JS-002:2022
				Charged Device Model (CDM) Electrostatic Discharge (ESD) Test AEC-Q100-011 Rev-D:2019
				Charged Device Model (CDM) Electrostatic Discharge (ESD) Test AEC-Q101-005 Rev-A:2019
		13	LU	IC Latch-Up Test JESD78F.02: 2023
				IC Latch-Up Test AEC-Q100-004 Rev-D:2012
		14	WBP	Bond strength (destructive bond pull test) MIL-STD- 883L 2019
				Wire Bond Pull Test Methods JESD22-B120-2022
		15	WBS	Wire Bond Shear Test Method JESD22-B116B-2017
				Wire Bond Shear Test AEC-Q100-001-Rev-C:1998
				Wire Bond Shear Test AEC-Q101-003 Rev-A:2005
		16	SBS	Solder Ball Shear JESD22-B117B-2014 item 4
				Solder Ball Shear AEC-Q100-010-Rev-A: 2003
		17	DS	Die Shear Strength MIL-STD-883L:2019 method 2019.10
				Die Shear Strength Criteria MIL-STD-750-2B: 2022 method 2017.3
		18	NVM Endurance,Data Retention, and Operational Life	NVM Endurance,Data Retention, and Operational Life AEC - Q100-005 - REV-D1-2012
				Electrically Erasable Programmable ROM (EEPROM) Program / Erase Endurance and Data Retention Stress Test JESD22-A117E-2018

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